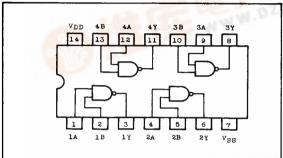
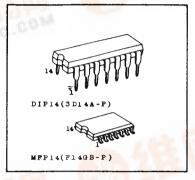
TOSHIBA INTEGRATED CIRCUIT TECHNICAL DATA

查询TC40H000P供应商 捷多邦 C²MOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC40H000 QUAD 2-INPUT NAND GATE

PIN CONNECTION





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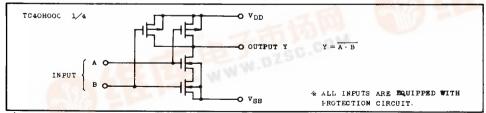
MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	VDD	V _{SS-0.5} ∿ V _{SS+10}	v
Input Voltage	VIN	VSS-0.5 ~ VDD+0.5	V
Output Voltage	VOUT	$v_{SS=0.5} \sim v_{DD=0.5}$	v
Input Current	IIN	±10	mA
Power Dissipation	PD	300(DIP)/130(MFP)	mW
Storage Temperature	Tstg	-65 ∿ 150	°C
Lead Temp./Time	Tsol	260°C · 10 sec	

TRUTH TABLE

INE	τu	OUTPUT
А	Ь	Y
L	L	н
н	L	н
L	н	н
н	н	L

CIRCUIT DIAGRAM



RECOMMENDED OPERATING CONDITIONS (V_{SS}=0V)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN:	TYP.	MAX.	UNIT
Supply Voltage	V _{DD}	-	2.0	-	8.0	v
Input Voltage	VIN	-	0	-	VDD	v
Operating Temperature	Topr	-	-40	-	85	°C

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ELECTRICAL CHARACTERISTICS(V_{SS}=0.0V)

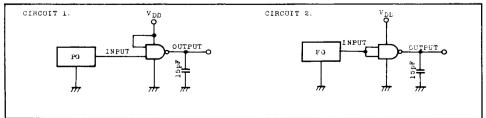
CHARACTERISTIC SYMBO	SYMBOL TEST CONDITION	V _{DD}	-40°C		25°C			85°C		UNIT	
	SIMBUL	TEST CONDITION	(V)	MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High Level Output Voltage	V _{OH}	^I OUT <1µA V _{IN=VSS} , V _{DD}	5	4.95	-	4.95	5.0	-	4.95	-	v
Low Level Output Voltage	v _{ol}	I _{OUT} <1µA V _{IN} =V _{DD}	5	-	0.05	-	0.0	0.05		0.05	
High Level Output Current	^I он	V _{OH} =4.6V V _{IN} =V _{SS} , V _{DD}	5	-0.52	-	-0.44		-	-0.36	-	πА
Low Level Output Current	I _{OL}	V _{OL} =0.4V V _{IN} =V _{DD}	5	1.4	-	1.1		-	0.8	-	
Input "H" Level	VIH	I _{OUT} <1µA	5	4.0	-	4.0		-	4.0	-	
Voltage Level	VIL	V _{OUT=0.5V} V _{OUT=4.5V}	5	-	1.0	-		1.0	-	1.0	v
Input "H" Level	IIH	V _{IH} =8.0V	8	-	0.3	-	10-5	0.3	-	1.0	μA
Current "L" Level	IIL	V _{IL} =0.0V	8	-	-0.3	-	-10 ⁻⁵	-0.3	-	-1.0] " "
Quiescent Supply Current	-00	*V _{IN} =V _{SS} , V _{DD}	5	-	2.0	-	10-3	2.0	-	10.0	μA

* All valid input combinations.

SWITCHING CHARACTERISTICS (Ta=25°C, VSS=0.0V, CL=15pF)

CHARACTERISTIC		SYMBOL	TEST CONDITION	V _{DD(V)}	MIN.	TYP.	MAX.	UNIT
Output Rise Time		tor	Circuit 1	5	-	26	40	
Output Fall Time		t _{of}	Circuit l	5	_	16	30	ns
Propagation Delay Time	(Low-High)	t _{pLH}	-	5	_	18	27	
	(High-Low)	tpHL	Circuit 1	5	-	14	21	ns
Propagation (Low-High)		tpLH		5	-	13	20	1
Delay Time	(High-Low)	t _{pHL}	Circuit 2	5	-	15	23	ns
Input Capacitance		CIN		•	-	5	-	pF

SWITCHING TIME TEST CIRCUIT



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SWITCHING TIME TEST WAVEFORM

